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RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2117

PATENT APPLICATION
Docket No.: 4591-363
Client Ref. No.: IB13018-US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Nam-Jung HER, et al.

Confirmation No.: 5596

Serial No.: 10/803,792

Examiner: Radosevich, Steven D.

Filed: March 17, 2004

Group Art Unit: 2138

For: SEMICONDUCTOR INTEGRATED CIRCUIT HAVING A NUMBER
OF DATA OUTPUT PINS CAPABLE OF SELECTIVELY PROVIDING
OUTPUT SIGNALS AND TEST METHOD THEREOF

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT AFTER FINAL REJECTION

Responsive to the Final Office Action dated May 8, 2007, please amend the application
as follows.

Claims begin on page 2.

Remarks begin on page 5.